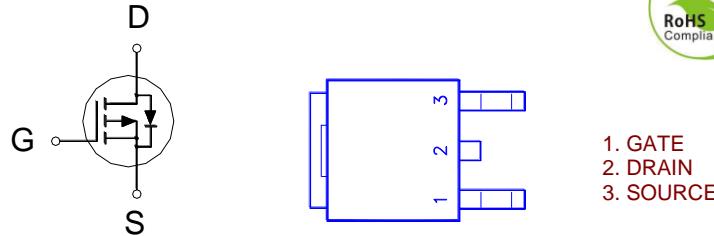


NIKO-SEM**P-Channel Logic Level Enhancement Mode
Field Effect Transistor****PA110ED**
TO-252
Halogen-Free & Lead-Free**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
-100V	110mΩ	-16A

**ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	-100	V
Gate-Source Voltage		V_{GS}	± 25	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	-16	A
	$T_C = 100^\circ\text{C}$		-10	
Pulsed Drain Current ¹		I_{DM}	-61	
Avalanche Current		I_{AS}	-14	
Avalanche Energy	$L = 1\text{mH}$	E_{AS}	98	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	62.5	W
	$T_C = 100^\circ\text{C}$		25	
Junction & Storage Temperature Range		T_J, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		50	°C / W
Junction-to-Case	$R_{\theta JC}$		2	

¹Pulse width limited by maximum junction temperature.

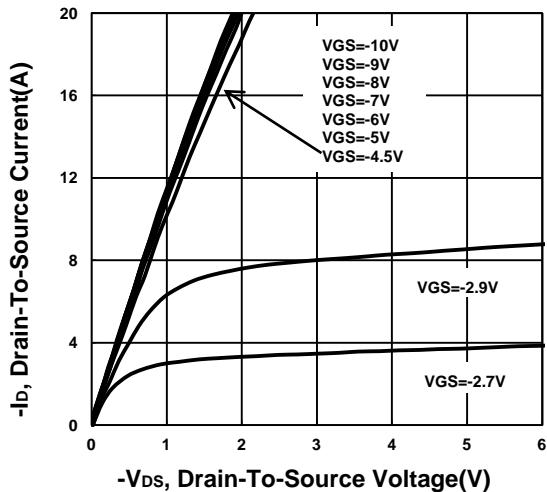
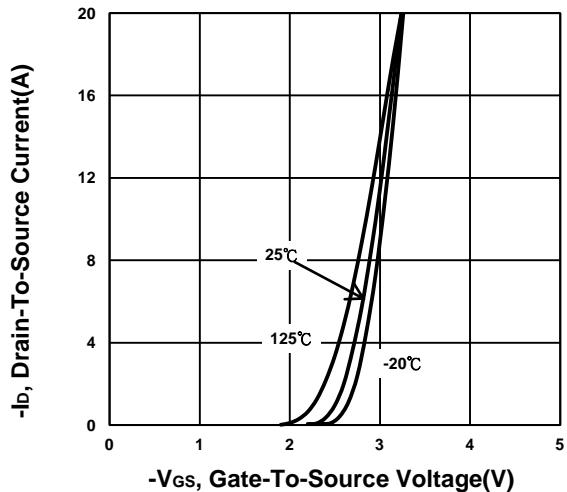
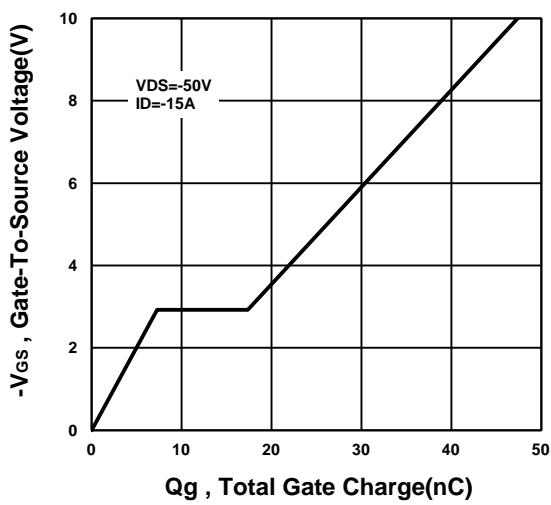
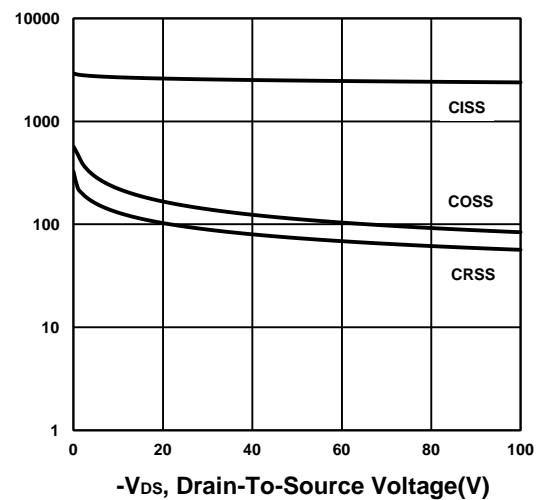
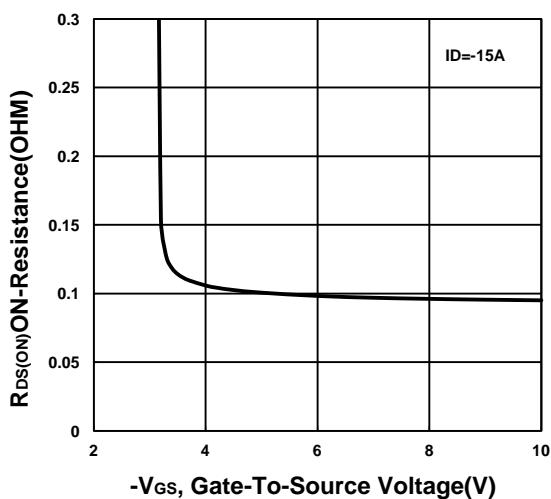
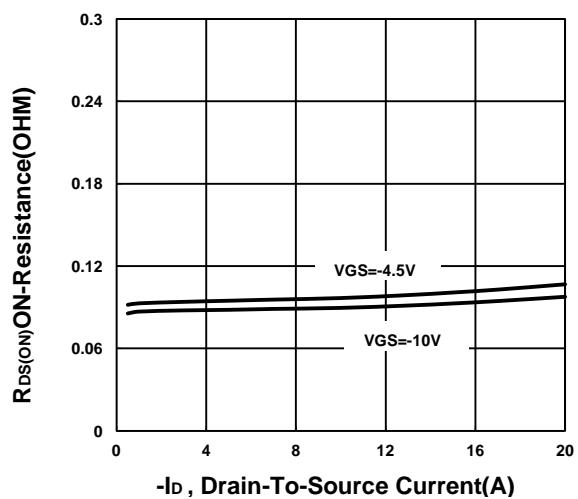
ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

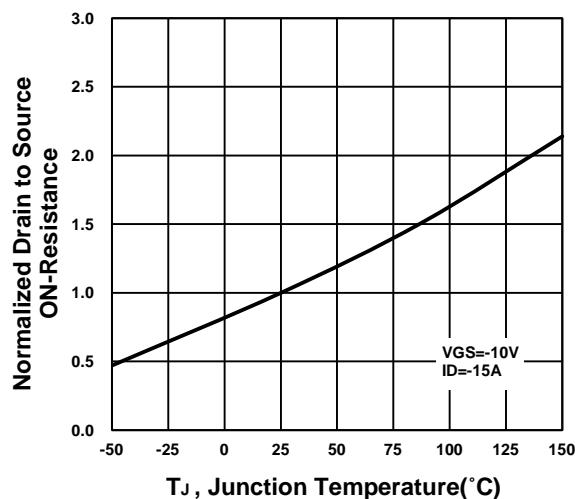
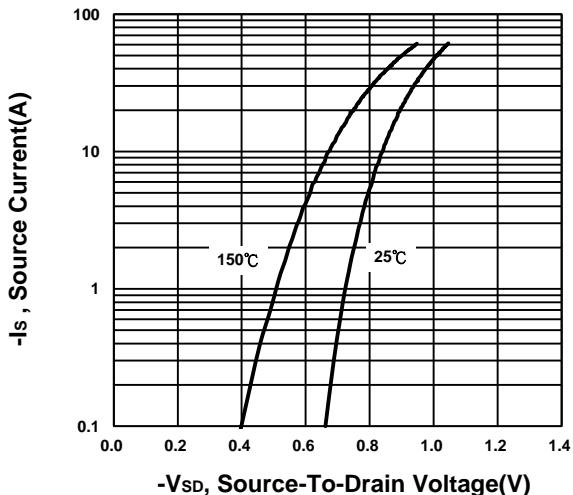
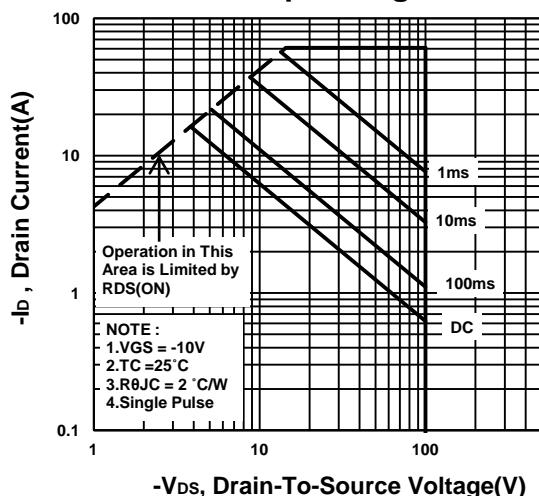
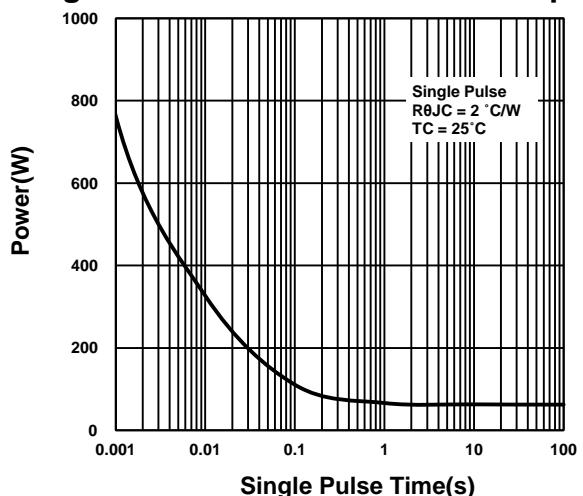
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = -250\mu\text{A}$	-100			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-1.3	-1.8	-2.3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 25\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -100\text{V}, V_{GS} = 0\text{V}$			-1	μA
		$V_{DS} = -100\text{V}, V_{GS} = 0\text{V}, T_J = 55^\circ\text{C}$			-10	

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Drain-Source On-State Resistance ¹	R _{DS(ON)}	V _{GS} = -4.5V, I _D = -10A		98	130	mΩ
		V _{GS} = -10V, I _D = -15A		94	110	
Forward Transconductance ¹	g _{fS}	V _{DS} = -5V, I _D = -15A		36		S
DYNAMIC						
Input Capacitance	C _{iss}	V _{GS} = 0V, V _{DS} = -50V, f = 1MHz		2498		pF
Output Capacitance	C _{oss}			112		
Reverse Transfer Capacitance	C _{rss}			73		
Gate Resistance	R _g	V _{GS} = 0V, V _{DS} = 0V, f = 1MHz		10.6		Ω
Total Gate Charge ²	Q _g	V _{DS} = -50V, V _{GS} = -10V, I _D = -15A		47		nC
Gate-Source Charge ²	Q _{gs}			7.3		
Gate-Drain Charge ²	Q _{gd}			10		
Turn-On Delay Time ²	t _{d(on)}	V _{DS} = -50V, I _D ≈ -15A, V _{GS} = -10V, R _{GEN} = 6Ω		9		nS
Rise Time ²	t _r			48		
Turn-Off Delay Time ²	t _{d(off)}			123		
Fall Time ²	t _f			82		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T_J = 25 °C)						
Continuous Current	I _S	I _F = -15A, V _{GS} = 0V			-16	A
Forward Voltage ¹	V _{SD}				-1.2	V
Reverse Recovery Time	t _{rr}			36		nS
Reverse Recovery Charge	Q _{rr}			72		nC

¹Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.²Independent of operating temperature.

NIKO-SEM**P-Channel Logic Level Enhancement Mode
Field Effect Transistor****PA110ED**
TO-252
Halogen-Free & Lead-Free**Output Characteristics****Transfer Characteristics****Gate charge Characteristics****Capacitance Characteristic****On-Resistance VS Gate-To-Source Voltage****On-Resistance VS Drain Current**

NIKO-SEM**P-Channel Logic Level Enhancement Mode
Field Effect Transistor****PA110ED
TO-252
Halogen-Free & Lead-Free****On-Resistance VS Temperature****Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**